

General Description

The AOTL66912 use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness.

General Features

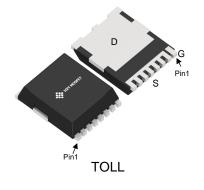
 $V_{DS} = 100V I_{D} = 350A$

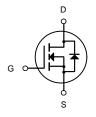
 $R_{DS(ON)} < 2m\Omega$ @ $V_{GS}=10V$

Applications

Battery Protection

Power Distribution





N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
AOTL66912	TOLL	HXY MOSFET	2000

Absolute Maximum Ratings at Tj=25°C unless otherwise noted

Parameter		Symbol	Value	Unit	
Drain-Source Voltage		V _{DS}	100	V	
Gate-Source Voltage		V _G s	±20	V	
Continuous Drain Current	T _C =25°C		350	А	
Continuous Drain Current	T _C =100°C	- I _D	200		
Pulsed Drain Current ¹		I _{DM}	1248	А	
Single Pulse Avalanche Energy ²		EAS	1250	mJ	
Total Power Dissipation Tc=25°C		P _D	390.6	W	
Operating Junction and Storage Temperature Range		TJ, TSTG	J, T _{STG} -55 to 150		
Thermal Resistance from Junction-to-Ambient ³		R _{θJA}	R ₀ JA 39		
Thermal Resistance from Junction-to-Case		R ₀ JC	0.32	°C/W	



Electrical Characteristics (T_J = 25°C, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static Characteristics				1				
Drain-Source Breakdown Voltage		V _{(BR)DSS}	V _{GS} = 0V, I _D = 250µA	100	-	-	V	
Gate-body Leakage current		Igss	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA	
Zero Gate Voltage Drain Current	T _J =25°C		V _{DS} = 100V, V _{GS} = 0V	-	-	1	μΑ	
	T _J =100°C	IDSS		-	-	100		
Gate-Threshold Voltage		V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	3	4	V	
Drain-Source on-Resistance ⁴	ı	R _{DS(on)}	V _{GS} = 10V, I _D = 20A	-	1.4	2.0	mΩ	
Forward Transconductance ⁴		G fs	V _{DS} = 10V, I _D =20A	-	84	-	S	
Dynamic Characteristics	5			•				
Input Capacitance		Ciss		-	14300	-		
Output Capacitance		Coss	V _{DS} = 50V, V _{GS} =0V, f =1MHz	-	2120	-	pF	
Reverse Transfer Capacitance		Crss		-	50	-		
Gate Resistance		R_g	f=1MHz	-	2.8	-	Ω	
Switching Characteristic	: s ⁵			•				
Total Gate Charge		Qg	V _{GS} = 10V, V _{DS} = 50V, I _D = 20A	-	250	-	nC	
Gate-Source Charge		Q _{gs}		-	53	-		
Gate-Drain Charge		Q _{gd}		-	77	-		
Turn-on Delay Time		t _{d(on)}		-	41	-		
Rise Time		t _r	$V_{GS} = 10V, V_{DD} = 50V,$ $R_{G} = 3\Omega, I_{D} = 20A$	-	88	-	ns ns	
Turn-off Delay Time		t _{d(off)}		-	163	-		
Fall Time		t _f		-	98	-		
Body Diode Reverse Recovery Time		t _{rr}		-	106	-	ns	
Body Diode Reverse Recovery Charge		Qrr	- I _F =20A, di/dt = 100A/μs	-	245	-	nC	
Drain-Source Body Diod	e Character	istics						
Diode Forward Voltage ⁴		VsD	I _S = 20A, V _{GS} = 0V	-	-	1.2	V	
Continuous Source Current	T _C =25°C	Is	-	-	-	350	Α	

Note:

- A. The maximum current rating is package limited.
- B. Repetitive rating; pulse width limited by max. junction temperature.
- C. V_{DD} =32 V, R_G =25 Ω , L=0.5mH, starting T_j =25 $^{\circ}$ C.
- $\label{eq:DD} \textbf{D.} \quad \textbf{P}_{\textbf{D}} \text{ is based on max. junction temperature, using junction-case thermal resistance.}$
- E. The value of R_{BJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with Ta=25°C.



Typical Characteristics

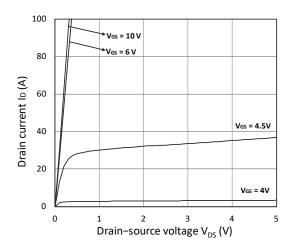


Figure 1. Output Characteristics

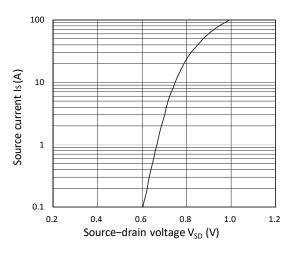


Figure 3. Forward Characteristics of Reverse

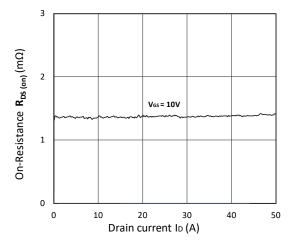


Figure 5. $R_{DS(ON)}$ vs. I_D

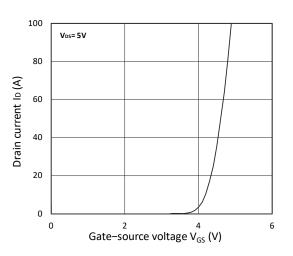


Figure 2. Transfer Characteristics

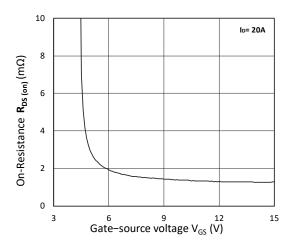


Figure 4. $R_{DS(ON)}$ vs. V_{GS}

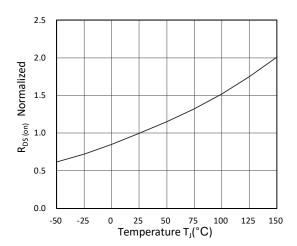
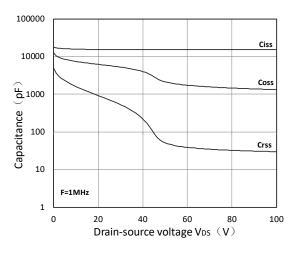
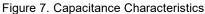


Figure 6. Normalized $R_{\text{DS(on)}}$ vs. Temperature





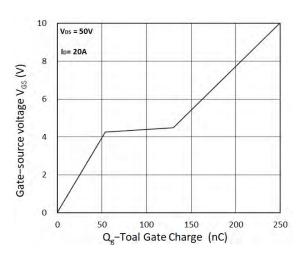


Figure 8. Gate Charge Characteristics

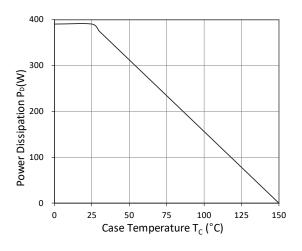


Figure 9. Power Dissipation

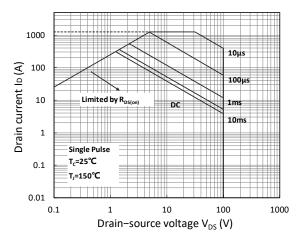


Figure 10. Safe Operating Area

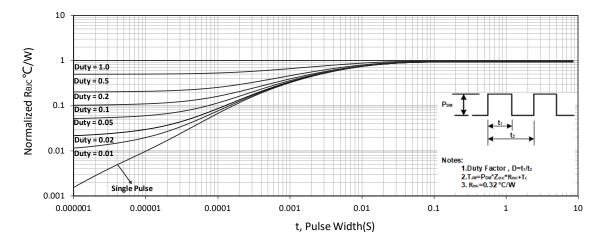
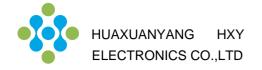


Figure 11. Normalized Maximum Transient Thermal Impedance



Test Circuit

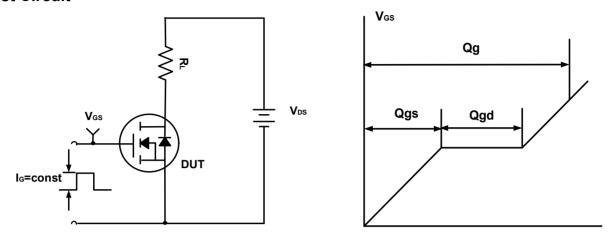


Figure A. Gate Charge Test Circuit & Waveforms

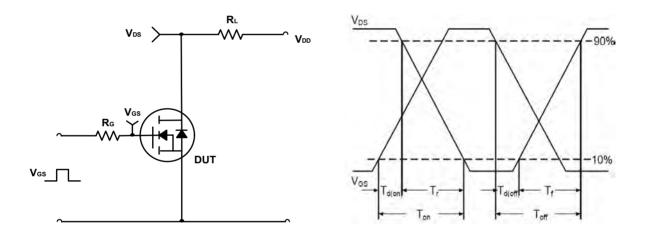


Figure B. Switching Test Circuit & Waveforms

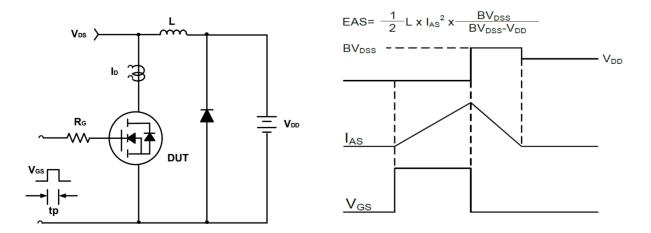
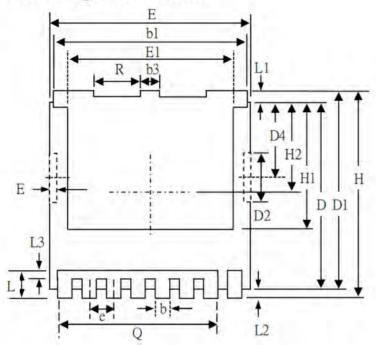


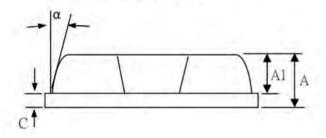
Figure C. Unclamped Inductive Switching Circuit & Waveforms



TOLL Package Information



BACKSIDE VIEW



- 1.All Dimension Are In Millimeters.
- 2.Dimension Does Not Include Mold Protrusions.

SYMBOLS	MIN	NOM	MAX	
A	2.20	2.30	2.40	
A1	1.70	1.80	1.90	
b	0.70	0.80	0.90	
bl	9.70	9.80	9.90	
b3	1.10	1.20	1.30	
c	0.40	0.50	0.60	
D	10.28	10.38	10.58	
D1	9.80	11.08	11.80	
D2	3.10	3.30	3.50	
D4	4.37	4.55	4.77	
E	9.70	9.90	10.10	
E1	7.90	8.10	8.30	
E2	0.50	0.70	0.90	
e	1.20BCS			
Н	11.48 11.68		11.88	
Hl	6.95BCS			
H2	5.89BCS			
L	1.40	1.90	2.10	
Ll	0.60	0.70	0.80	
L2	0.50	0.60	0.70	
L3	0.30	0.70	1.30	
Q	8.00 REF.			
R	2.95	3.10	3.25	
α	4°		10°	



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